

**Search Notes**

Application/Control No.

10/732,751

Examiner

MICHAEL Y. WON

Applicant(s)/Patent under  
Reexamination

CHAN ET AL.

Art Unit

2155

**SEARCHED**

Class	Subclass	Date	Examiner
709	203, 212, 217, 219, 228, 229	5/16/2008	MW

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
709	228	5/16/2008	MW

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST: USPAT; USPG-PUB; DERWENT; EPO; JPO	5/16/2008	MW
NPL SEARCH: IEEE	5/16/2008	MW